

**Search Notes**

Application/Control No.

10/554,267

Examiner

Marlon A. Arce-Diaz

Applicant(s)/Patent under  
Reexamination

TAKEMURA ET AL.

Art Unit

3611

**SEARCHED**

Class	Subclass	Date	Examiner
180	8.1,8.6, 8.5	12/6/2007	MAA
901	1,701	12/6/2007	MAA

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR